

	Search Terms
1	ALTER
2	ALTERED
3	ALTEREDS
4	ALTERING
5	ALTERINGS
6	ALTERS
7	AREA
8	AREAS
9	CHANGE
10	CHANGED
11	CHANGEDS
12	CHANGES
13	CHANGING
14	CHANGINGS
15	CIRCUIT
16	CIRCUITS
17	FAIL
18	FAILED
19	FAILED
20	FAILING
21	FAILINGS
22	FAILS
23	FAILURE
24	FAILURES
25	FAULT
26	FAULTIES
27	FAULTS
28	FAULTY
29	FAULTYS
30	LOGIC
31	LOGICS
32	NUMBER
33	NUMBERS

	Total	US-PGPUB	USPAT	USOCR	EPO	JPO	Derwent	IBM TDB
1	349423							
2	351636							
3	0							
4	231046							
5	10							
6	79524							
7	3398267							
8	1264538							
9	2479088							
10	1222329							
11	7							
12	2575404							
13	1202101							
14	194							
15	3947741							
16	1195854							
17	315466							
18	161192							
19	0							
20	60466							
21	1287							
22	216095							
23	623505							
24	95205							
25	201665							
26	4							
27	76046							
28	80081							
29	0							
30	566270							
31	5118							
32	4938000							
33	1208613							

	Search Terms
34	TESTCASE
35	TESTCASES
36	((((TESTCASE SAME (FAILING OR FAULTY OR FAILED OR FAIL OR FAULT OR FAILURE)) AND ((LOGIC SAME AREA) SAME (ALTERING OR ALTER OR ALTERED OR CHANGED OR CHANGING OR CHANGE) SAME CIRCUIT)) AND (LOGIC SAME AREA SAME NUMBER)))

	Total	US-PGPUB	USPAT	USOCR	EPO	JPO	Derwent	IBM TDB
34	234							
35	169							
36	0							

	Search Terms
1	ALTER
2	ALTERED
3	ALTEREDS
4	ALTERING
5	ALTERINGS
6	ALTERS
7	LOGIC
8	LOGICS
9	NORMAN-JASON
10	NORMAN-JASONS
11	PRATT-NANCIES
12	PRATT-NANCY
13	PRATT-NANCYS
14	RO
15	ROE
16	ROES
17	ROS
18	TESTCASE
19	TESTCASES
20	VENTRONE-SEBASTIAN
21	VENTRONE-SEBASTIANS
22	((((NORMAN-JASON.IN.) OR (PRATT-NANCY.IN.)) OR (VENTRONE-SEBASTIAN.IN.)) AND TESTCASE) AND (ALTERING OR ALTER OR ALTERED OR RO) AND LOGIC)

	Total	US-PGPUB	USPAT	USOCR	EPO	JPO	Derwent	IBM TDB
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2	351636							
3	0							
4	231046							
5	10							
6	79524							
7	566270							
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14	1560107							
15	26701							
16	1829							
17	15244							
18	234							
19	169							
20	6							
21	0							
22	0							

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Example: optical <and> (fiber <or> fibre) <in> ti
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(testcase<or>testcases) <and>
(logic<paragraph>areas<paragraph>number) <and> circuit

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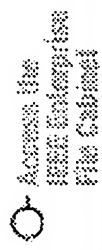
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Search

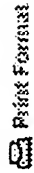
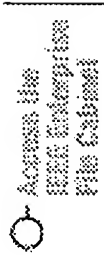
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